

Functional Safety Information

**TPSM82821, TPSM82822, TPSM82823, TPSM82821A,  
TPSM82822A, and TPSM82823A**

**Pin Failure Mode Analysis (Pin FMA)**



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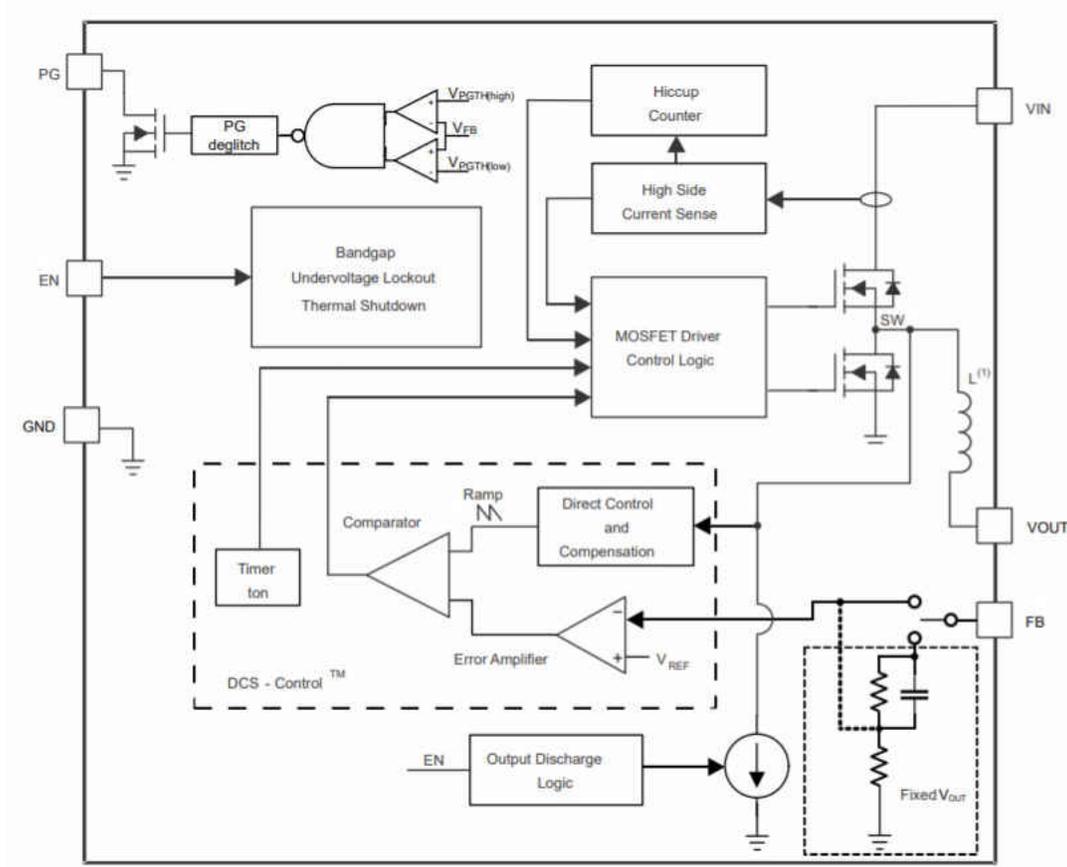
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## 1 Overview

This document contains the Pin failure mode analysis (pin FMA) information for the TPSM82821, TPSM82822, TPSM82823, TPSM82821A, TPSM82822A, and TPSM82823A (uSiP package).

Figure 1-1 shows the device functional block diagram for reference.



**Figure 1-1. Functional Block Diagram**

The TPSM8282x was developed using a quality-managed development process, but was not developed in accordance with the IEC 61508 or ISO 26262 standards.

## 2 Pin Failure Mode Analysis (Pin FMA)

This section provides a failure mode analysis (FMA) for the pins of the TPSM8282x. The failure modes covered in this document include the typical pin-by-pin failure scenarios:

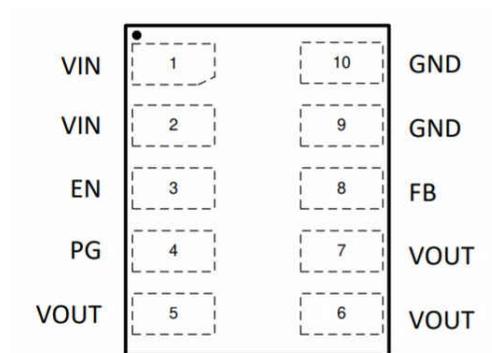
- Pin short-circuited to ground (see [Table 2-2](#))
- Pin open-circuited (see [Table 2-3](#))
- Pin short-circuited to an adjacent pin (see [Table 2-4](#))
- Pin short-circuited to VIN (see [Table 2-5](#))

[Table 2-2](#) through [Table 2-5](#) also indicate how these pin conditions can affect the device as per the failure effects classification in [Table 2-1](#).

**Table 2-1. TI Classification of Failure Effects**

Class	Failure Effects
A	Potential device damage that affects functionality.
B	No device damage, but loss of functionality.
C	No device damage, but performance degradation.
D	No device damage, no impact to functionality or performance.

[Figure 2-1](#) shows the TPSM8282x pin diagram. For a detailed description of the device pins, see the *Pin Configuration and Functions* section in the TPSM8282x data sheet.



**Figure 2-1. Pin Diagram**

Following are the assumptions of use and the device configuration assumed for the pin FMA in this section:

- The device is operating in the typical application, please refer to the *Simplified Application* on the first page in the TPSM8282x datasheet.

**Table 2-2. Pin FMA for Device Pins Short-Circuited to Ground**

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
VIN	1,2	Device will not be powered up	A
EN	3	Device will not be enabled	B
PG	4	Loss of PG functionality	B
VOUT	5,6,7	Device not functional	A
FB	8	Output voltage will not be regulated. Device will enter 100% mode.	B
GND	9,10	Intended functionality	D

**Table 2-3. Pin FMA for Device Pins Open-Circuited**

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
VIN	1,2	Redundant pin. If one of the pins are open, no functionality loss but potential impact on device performance	C
EN	3	Undetermined state of the pin; device may or may not be enabled	B
PG	4	Loss of PG functionality	B
VOUT	5,6,7	Redundant pin. If one of the pins are open, no functionality loss but potential impact on device performance	C
FB	8	Device not functional; Open loop operation	B
GND	9,10	Redundant pin. If one of the pins are open, no functionality loss but potential impact on device performance	C

**Table 2-4. Pin FMA for Device Pins Short-Circuited to Adjacent Pin**

Pin Name	Pin No.	Shorted to	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
VIN	2	EN	3	Loss of Enable functionality	B
EN	3	PG	4	Loss of Enable functionality; Potential device damage	A
PG	4	VOUT	5	Loss of PG functionality; Potential device damage	A
VOUT	7	FB	8	For adjustable versions output voltage will be regulated to 0.6V (Intended functionality for Fixed Vout devices)	B
FB	8	GND	9	Output voltage will not be regulated. Device will enter 100% mode.	B

**Table 2-5. Pin FMA for Device Pins Short-Circuited to VIN**

Pin Name	Pin No.	Description of Potential Failure Effect(s)	Failure Effect Class
VIN	1	Intended functionality	D
EN	3	Loss of Enable functionality	B
PG	4	Loss of PG functionality; Potential device damage	A
VOUT	5,6,7	Potential device damage	A
FB	8	Device not functional; Open loop operation	B
GND	9,10	Potential device damage	A

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